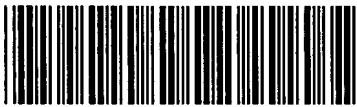


<b>Search Notes</b>  	<b>Application/Control No.</b>  10500355	<b>Applicant(s)/Patent Under Reexamination</b>  KOBAYASHI ET AL.
	<b>Examiner</b>  Kim, Jennifer	<b>Art Unit</b>  1617

SEARCHED			
Class	Subclass	Date	Examiner
514	688,699,738,729	3/19/2007	jmk
	updated	9/14/2007	jmk

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor serach; STN; WEST	3/19/2007	jmk
STIC; updated	9/14/2007	jmk

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner